

## CONSUMER LEVEL QUALIFICATION REQUIREMENTS FOR IC PRODUCTS

Stress Test	Conditions	Duration	Sample Size <sup>1</sup>
Temperature Cycle (TC)	-40°C/125°C or -65°C/150°C 30 minute cycles	500 cycles  250 cycles	3 lots x 77 devices
Temperature and Humidity Bias (THB)  <i>High Accelerated Temperature and Humidity Stress Test (HAST)</i>	85°C/85%RH  <i>130°C/85%RH/18.6Psig</i>  Biased up to 100% Vmax (Not to exceed 100V for THB and 42V for HAST)	500 hours  <i>96 hours</i>	3 lots x 77 devices
High Temperature Operating Life (HTOL)	T <sub>j</sub> =125°C or T <sub>j</sub> =150 °C Biased up to 100% Vmax (static or dynamic)	500 hours  <i>336 hours</i>	3 lots x 77 devices
High Temperature Storage Life (HTSL)	T <sub>a</sub> =150°, no bias or T <sub>a</sub> =175°C, no bias	500 hours  <i>240 hours</i>	1 lot x 45 devices

1 – Family data may be used to qualify one or more products

### PRECONDITIONING REQUIREMENTS

Minimum MSL3 preconditioning per JESD22-A113 is required for surface mount capable devices that are put on TC and THB/HAST.

### FAILURE CRITERIA

All devices parameters must pass the data sheet specification requirements